

FDR836P

P-Channel 2.5V Specified MOSFET

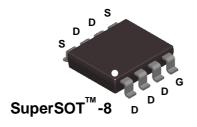
General Description

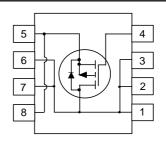
SuperSOTTM -8 P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance and provide superior switching performance. These devices are particularly suited for low voltage applications such as battery powered circuits or portable electronics where low in-line power loss, fast switching and resistance to transients are needed.

Features

• -6.1 A, -20 V.
$$R_{DS(ON)} = 0.030 \text{ W} @ V_{GS} = -4.5 \text{ V}$$
 $R_{DS(ON)} = 0.040 \text{ W} @ V_{GS} = -2.5 \text{ V}$

- High density cell design for extremely low R_{DS(ON)}.
- Small footprint (38% smaller than a standard SO-8); low profile package (1 mm thick); power handling capability similar to SO-8.





Absolute Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter	Ratings	Units	
V _{DSS}	Drain-Source Voltage		-20	V
V_{GSS}	Gate-Source Voltage		<u>+</u> 8	V
I _D	Drain Current - Continuous	(Note 1a)	-6.1	Α
	- Pulsed		-18	
P _D	Power Dissipation for Single Operation	(Note 1a)	1.8	W
		(Note 1b)	1.0	
		(Note 1c)	0.9	
T _J , T _{stg}	Operating and Storage Junction Temperatu	-55 to +150	°C	

Thermal Characteristics

$R_{\theta^{JA}}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	70	°C/W
R _{AJC}	Thermal Resistance, Junction-to-Case	(Note 1)	20	°C/W

Package Outlines and Ordering Information

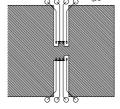
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Device Marking	Device	Reel Size	Tape Width	Quantity					
_836P	FDR836P	13"	12mm	3000 units					

ă 1999 Fairchild Semiconductor Corporation FDR836P, Rev. C

Symbol	Parameter	Min	Тур	Max	Units	
Off Char	acteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$	-20			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	$I_{D}\text{=}$ -250 $\mu\text{A},$ Referenced to 25°C		-24		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -16 \text{ V}, V_{GS} = 0 \text{ V}$			-1	μΑ
I_{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS} = 8 \text{ V}, V_{DS} = 0 \text{ V}$			100	nA
I_{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -8 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
On Char	racteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	-0.4	-0.6	-1	V
$\Delta V_{GS(th)} \over \Delta T_{J}$	Gate Threshold Voltage Temperature Coefficient	I_D = -250 μ A, Referenced to 25°C		3		mV/°C
R _{DS(on)}	Static Drain-Source On-Resistance	$V_{GS} = -4.5 \text{ V}, I_D = -6.1 \text{ A}$ $V_{GS} = -4.5 \text{ V}, I_D = -6.1 \text{ A}, T_J = 125 ^{\circ}\text{C}$ $V_{GS} = -2.5 \text{ V}, I_D = -5 \text{ A}$		0.022 0.031 0.029	0.030 0.048 0.040	Ω
I _{D(on)}	On-State Drain Current	V _{GS} = -4.5 V, V _{DS} = -5 V	-9			Α
g _{FS}	Forward Transconductance	$V_{DS} = -5 \text{ V}, I_{D} = -6.1 \text{A}$		22		S
Dvnamio	Characteristics					
C _{iss}	Input Capacitance	$V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V},$		2200		pF
Coss	Output Capacitance	f = 1.0 MHz		570		pF
C _{rss}	Reverse Transfer Capacitance			140		pF
Switchir	ng Characteristics (Note 2)					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = -10 \text{ V}, I_{D} = -1 \text{ A},$		10	18	ns
t _r	Turn-On Rise Time	$V_{GS} = -4.5 \text{ V}, R_{GEN} = 6 \Omega$		14	25	ns
t _{d(off)}	Turn-Off Delay Time			225	360	ns
t _f	Turn-Off Fall Time			85	135	ns
$\overline{Q_g}$	Total Gate Charge	$V_{DS} = -10 \text{ V}, I_{D} = -6.1 \text{ A},$		32	44	nC
$\overline{Q_gs}$	Gate-Source Charge	V _{GS} = - 4.5 V		3.2		nC
$\overline{Q_{gd}}$	Gate-Drain Charge			8.1		nC
Drain-So	ource Diode Characteristics and	d Maximum Ratings				
I _s	Maximum Continuous Drain-Source Did	_			-1.5	Α
V _{SD}	Drain-Source Diode Forward Voltage		-0.65	-1.2	V	

Notes

1. R_{QJA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain Pins. R_{QCA} is guaranteed by design while R_{QCA} is determined by the user's board design.



a) 70 °C/W when mounted on a 1.0 in² pad of 2 oz. copper.



b) 125 °C/W when mounted on a 0.026 in² pad of 2oz. copper.



c) 135 °C/W when mounted on a minimum pad.

Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width £ 300 ms, Duty Cycle £ 2.0%

Typical Characteristics

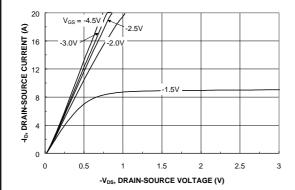


Figure 1. On-Region Characteristics.

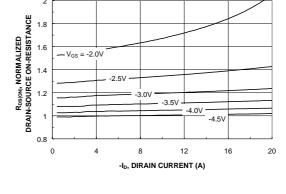


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

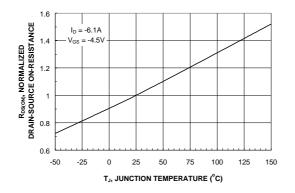


Figure 3. On-Resistance Variation with Temperature.

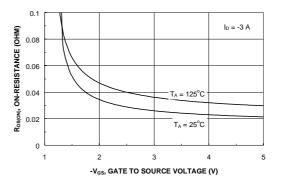


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

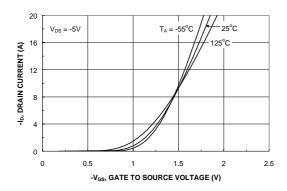


Figure 5. Transfer Characteristics.

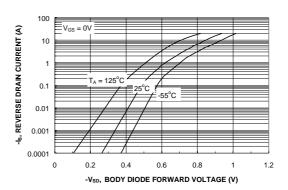
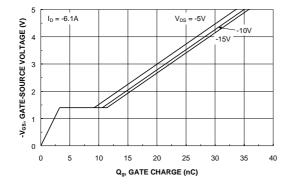


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics (continued)



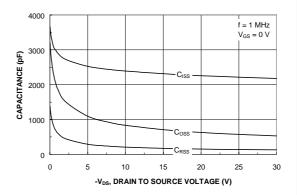
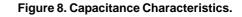
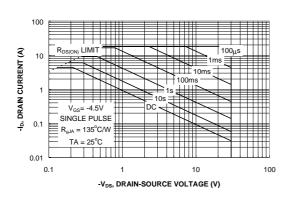


Figure 7. Gate-Charge Characteristics.





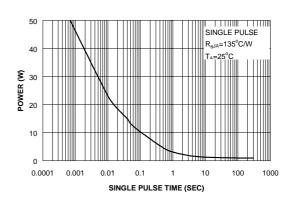


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

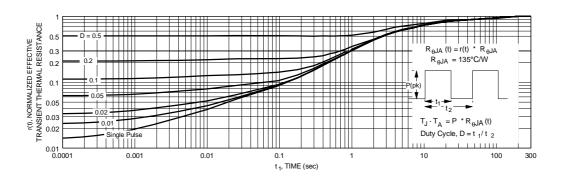
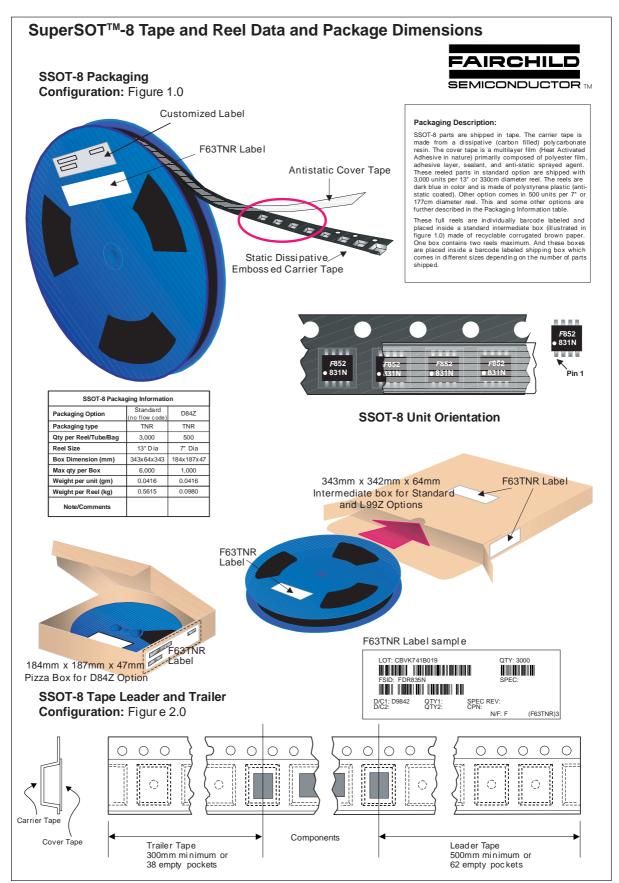


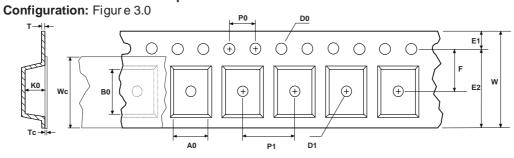
Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient themal response will change depending on the circuit board design.





SSOT-8 Embossed Carrier Tape



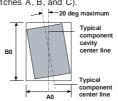
User Direction of Feed	

Dimensions are in millimeter														
Pkg type	Α0	В0	w	D0	D1	E1	E2	F	P1	P0	K0	т	Wc	Тс
SSOT-8 (12mm)	4.47 +/-0.10	5.00 +/-0.10	12.0 +/-0.3	1.55 +/-0.05	1.50 +/-0.10	1.75 +/-0.10	10.25 min	5.50 +/-0.05	8.0 +/-0.1	4.0 +/-0.1	1.37 +/-0.10	0.280 +/-0.150	9.5 +/-0.025	0.06 +/-0.02

Notes: A0, B0, and K0 dimensions are determined with respect to the EIA/Jedec RS-481 rotational and lateral movement requirements (see sketches A, B, and C).



Sketch A (Side or Front Sectional View)
Component Rotation

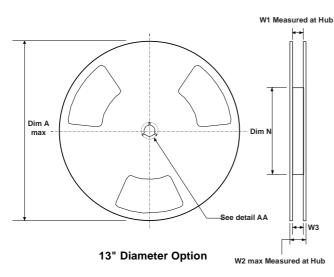


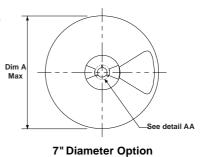
Sketch B (Top View)
Component Rotation



Sketch C (Top View)
Component lateral movement

SSOT-8 Reel Configuration: Figur e 4.0



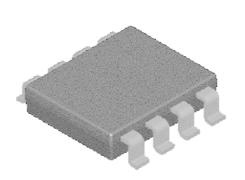


Dim D min DETAIL AA

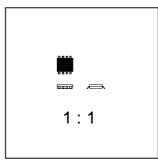
	Dimensions are in inches and millimeters									
Tape Size	Reel Option	Dim A	Dim B	Dim C	Dim D	Dim N	Dim W1	Dim W2	Dim W3 (LSL-USL)	
12mm	7" Dia	7.00 177.8	0.059 1.5	512 +0.020/-0.008 13 +0.5/-0.2	0.795 20.2	5.906 150	0.488 +0.078/-0.000 12.4 +2/0	0.724 18.4	0.469 - 0.606 11.9 - 15.4	
12mm	13" Dia	13.00 330	0.059 1.5	512 +0.020/-0.008 13 +0.5/-0.2	0.795 20.2	7.00 178	0.488 +0.078/-0.000 12.4 +2/0	0.724 18.4	0.469 - 0.606 11.9 - 15.4	

SuperSOT[™]-8 Tape and Reel Data and Package Dimensions, continued

SuperSOT™-8 (FS PKG Code 34, 35)



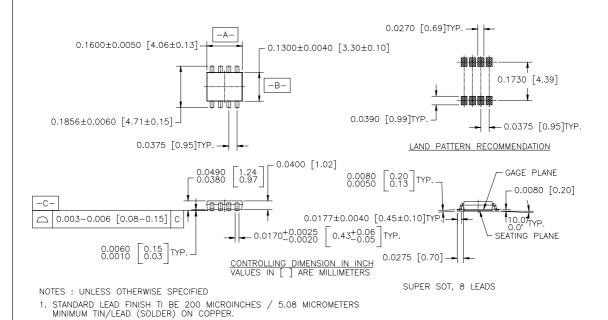
2. NO JEDEC REGISTRATION AS JAN. 1996



Scale 1:1 on letter size paper

Dimensions shown below are in: inches [millimeters]

Part Weight per unit (gram): 0.0416



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